

SN54120, SN74120 DUAL PULSE SYNCHRONIZERS/DRIVERS

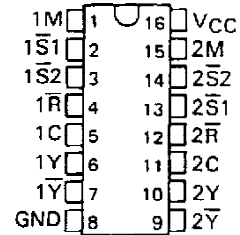
SDLS041

SEPTEMBER 1971 — REVISED MARCH 1988

- Generates Either a Single Pulse or Train of Pulses Synchronized with Control Functions
- Ideal for Implementing Sync-Control Circuits Similar to those Used in Oscilloscopes
- Latched Operation Ensures that Output Pulses Are Not Clipped
- High-Fan-Out Complementary Outputs Drive System Clock Lines Directly
- Internal Input Pull-Up Resistors Eliminate Need for External Components
- Diode-Clamped Inputs Simplify System Design
- Typical Propagation Delays:

9 Nanoseconds through One Level
16 Nanoseconds through Two Levels

SN54120 . . . J PACKAGE
SN74120 . . . N PACKAGE
(TOP VIEW)



description

These monolithic pulse synchronizers are designed to synchronize an asynchronous or manual signal with a system clock. Reliable response is ensured as the input signals are latched up; therefore duration of logic input is not critical and the adverse effects of contact-bounce of a manual input are eliminated. The ability to pass output pulses is started and stopped by the levels or pulses applied to the latch inputs $\bar{S}1$, $\bar{S}2$, or \bar{R} in accordance with the function table. High-speed circuitry is utilized throughout the clock paths to minimize skew with respect to the system clock.

After initiation, the mode control (M) input determines whether a series of pulses or only one pulse is passed. In the absence of a stop command, the clock driver will continue to pass clock pulses as long as the mode control input is low (see Figures 2 through 4). After the mode control input is taken high, only a single clock pulse will be passed (see Figure 5).

When the mode control is set to pass a series of pulses, the last pulse out is determined by two general rules:

- a. When pulses are terminated by the \bar{S} or \bar{R} inputs, conditions meeting the setup times (specified under recommended operating conditions) will dominate.
- b. Low-to-high-level transitions at the mode control input should be avoided during the 20-nanosecond period immediately following the negative transition of the input clock pulse as transitions during this time period may or may not allow the next pulse to pass (see Figures 4 and 5). When pulses are terminated by the mode control input, a positive transition at the mode control input meeting the high-level setup time, $t_{SU}(H)$, (specified under recommended operating conditions) will pass that positive clock pulse then inhibit remaining clock pulses. The clock input (C) is latch-controlled ensuring that once initiated the output pulse will not be terminated until the full pulse has been passed.

FUNCTION TABLE

INPUTS			FUNCTION
\bar{R}	$\bar{S}1$	$\bar{S}2$	
X	L	X	Pass Output Pulses
X	X	L	Pass Output Pulses
L	H	H	Inhibit Output Pulses
H	↓	H	Start Output Pulses
H	H	↓	Start Output Pulses
↓	H	H	Stop Output Pulses
H	H	H	Continue†

H = high level (steady state)

L = low level (steady state)

↓ = transition from H to L

X = irrelevant

† Operation initiated by last ↓ transition continues.

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**TEXAS
INSTRUMENTS**

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SN54120, SN74120 DUAL PULSE SYNCHRONIZERS/DRIVERS

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage	5.5 V
Interemitter voltage (see Note 2)	5.5 V
Operating free-air temperature range: SN54120 Circuits	-55°C to 125°C
SN74120 Circuits	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal.

2. This is the voltage between two emitters of a multiple-emitter transistor. For this circuit, this rating applies between the S1 and S2 inputs.

recommended operating conditions

		SN54120			SN74120			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX		
Supply voltage, V_{CC}		4.5	5	5.5	4.75	5	5.25	V	
High-level output current, I_{OH}		-2.4			-2.4			mA	
Low-level output current, I_{OL}		48			48			mA	
Setup time (see Figures 2 thru 5)	Any input except mode control, $t_{su}(H \text{ or } L)$	12			12			ns	
	Mode control	$t_{su}(H)$	0			0			
		$t_{su}(L)$	12			12			
Hold time (see Figures 3 and 5)	Any input except mode control, $t_h(H \text{ or } L)$	3			3			ns	
	Mode control, $t_h(H \text{ or } L)$	20			20				
Operating free-air temperature, T_A		-55			125			°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS [†]	MIN	TYP [‡]	MAX	UNIT
V_{IH}	High-level input voltage		2			V
V_{IL}	Low-level input voltage		0.8			V
V_{IK}	Input clamp voltage	$V_{CC} = \text{MIN}$, $I_I = -12 \text{ mA}$	-1.5			V
V_{OH}	High-level output voltage	$V_{CC} = \text{MIN}$, $V_{IH} = 2 \text{ V}$, $V_{IL} = 0.8 \text{ V}$, $I_{OH} = -2.4 \text{ mA}$	2.4	3.4		V
V_{OL}	Low-level output voltage	$V_{CC} = \text{MIN}$, $V_{IH} = 2 \text{ V}$, $V_{IL} = 0.8 \text{ V}$, $I_{OL} = 48 \text{ mA}$		0.2	0.4	V
I_I	Input current at maximum input voltage	$V_{CC} = \text{MAX}$, $V_I = 5.5 \text{ V}$	1			mA
I_{IH}	High-level input current	Clock input	80			μA
		Other inputs	$V_{CC} = \text{MAX}$, $V_I = 2.4 \text{ V}$	-0.12	-0.2	-0.36
I_{IL}	Low-level input current	Clock input	-3.2			mA
		Other inputs	$V_{CC} = \text{MAX}$, $V_I = 0.4 \text{ V}$	-2.1		
I_{OS}	Short-circuit output current [§]	$V_{CC} = \text{MAX}$	-35		-90	mA
I_{CC}	Supply current	$V_{CC} = \text{MAX}$. See Note 3	51		90	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$.

[§] Not more than one output should be shorted at a time.

NOTE 3: I_{CC} is measured with ground applied to all inputs except R which is at 4.5 V and all outputs open.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$

PARAMETER [¶]	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}	C	Y	$C_L = 45 \text{ pF}$, $R_L = 133 \Omega$, See Figure 1	14		22	ns
t_{PHL}				17		25	
t_{PLH}	C	\bar{Y}		10		16	ns
t_{PHL}				8		13	

[¶] t_{PLH} = Propagation delay time, low-to-high-level output

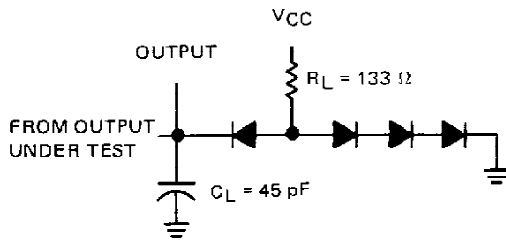
t_{PHL} = Propagation delay time, high-to-low-level output


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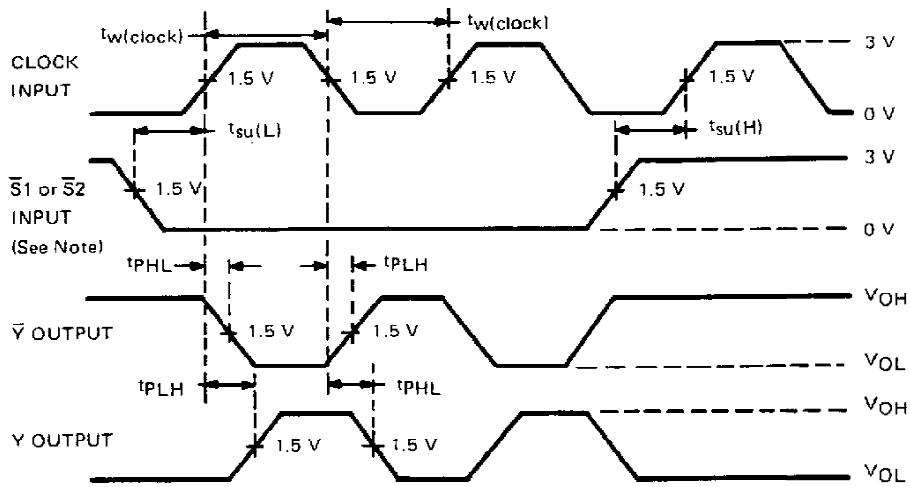
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PARAMETER MEASUREMENT INFORMATION



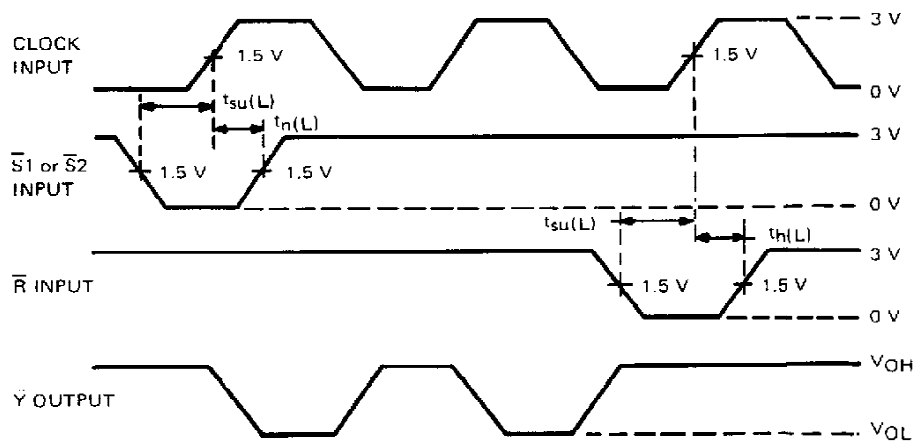
- NOTES: A. The clock input pulse in figures 2 through 5 is supplied by a generator having the following characteristics: $t_w(\text{clock}) \geq 15 \text{ ns}$, $\text{PRR} \leq 1 \text{ MHz}$, and $Z_{out} \approx 50 \Omega$.
 B. C_L includes probe and jig capacitance.
 C. All diodes are 1N3064 or equivalent.

FIGURE 1—LOAD CIRCUIT FOR SWITCHING TESTS



NOTE: Mode control and \bar{R} inputs are low and unused \bar{S} input is high.

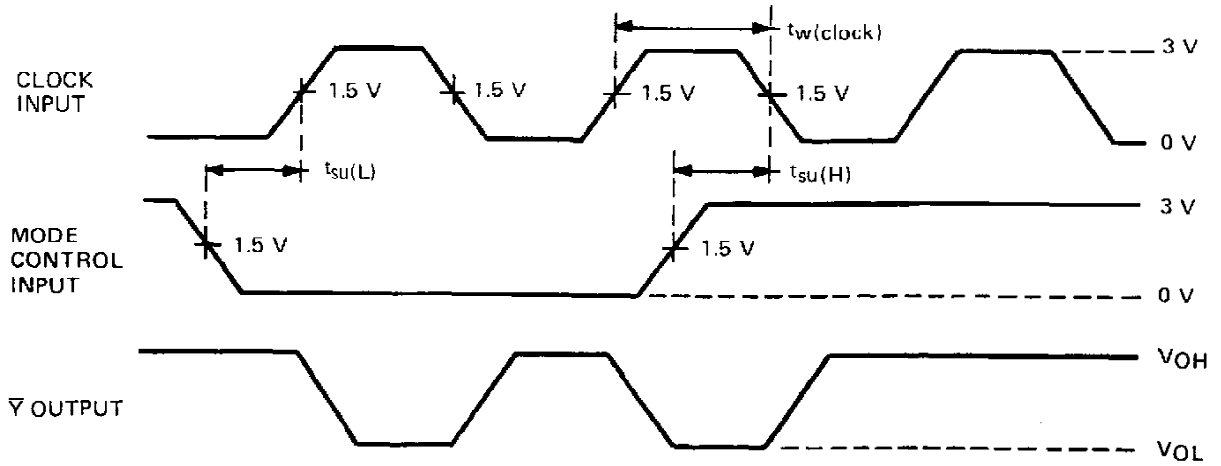
FIGURE 2—INITIATING AND TERMINATING PULSE TRAIN FROM S INPUTS



NOTE: Mode control input is low and unused \bar{S} input is high.

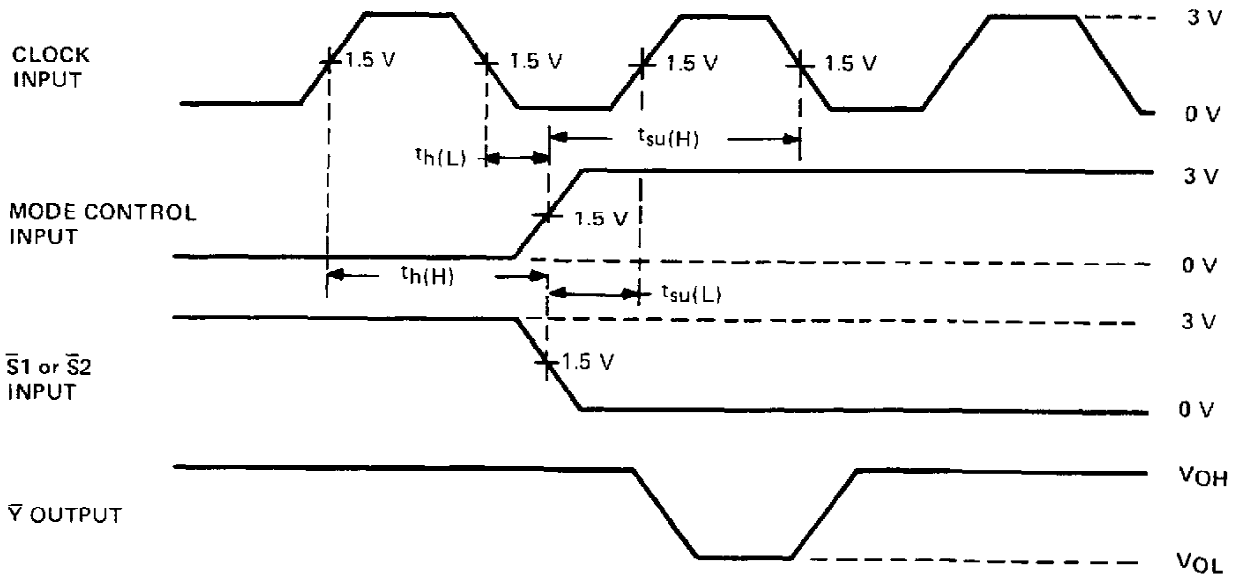
FIGURE 3—INITIATING PULSE TRAIN FROM S AND TERMINATING WITH R INPUTS

PARAMETER MEASUREMENT INFORMATION



NOTE: At least one of the \bar{S} inputs is low.

FIGURE 4—INITIATING AND TERMINATING PULSE TRAIN WITH MODE CONTROL INPUT



NOTE: Input \bar{R} is low and the unused \bar{S} input is high.

FIGURE 5—ENABLING SINGLE PULSE

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